

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

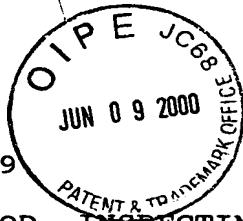
Applicant(s): IKEDA, et al.

Serial No.: 09/452,149

Filed: December 1, 1999

For: INSPECTING METHOD, INSPECTING SYSTEM, AND
METHOD FOR MANUFACTURING ELECTRONIC DEVICES

Group: 2721



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PRELIMINARY AMENDMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

June 9, 2000

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

IN THE SPECIFICATION

Please delete the original specification and substitute therefor the attached Substitute Specification.

IN THE CLAIMS

Please amend the claims as follows:

a, 55 310
1. (Amended) An inspecting system comprising an analyzing unit, said analyzing unit including an image detection device for [photographing] producing a plurality of images [in] of a workpiece; [a] storage means for storing detected images [detected] produced by said image detection device; [and a] display means having a screen with a first